### Feature

### N-Channel

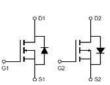
30V,20A

 $\begin{array}{l} R_{DS \ (ON)} < 14m \ \Omega \ @V_{GS} = 10V \ TYP: \ 10.5m \ \Omega \\ R_{DS \ (ON)} < 22m \ \Omega \ @V_{GS} = 4.5V \ TYP: \ 17m \ \Omega \end{array}$ 

### • P-Channel

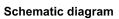
-30V,-20A Rds (ON) <23 m Ω @Vgs=-10V TYP: 17.5m Ω Rds (ON) <32 m Ω @Vgs=-4.5V TYP: 24 m Ω

- Lead free product is acquired
- High power and current handing capability
- Surface mount package



AIIPOWER

DATA SHEET





Marking and pin assignment

# Application

- PWM applications
- Load Switch
- Power management

## Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity (PCS)
3908QD	AP3908QD	PDFN3X3-D	-	-	5000

## ABSOLUTE MAXIMUM RATINGS (T<sub>J</sub>=25℃ unless otherwise noted)

Parameter	Symbol	N-Channel	P-Channel	Unit
Drain-Source Voltage	V <sub>DS</sub>	30	-30	V
Gate-Source Voltage	V <sub>GS</sub>	±20	±20	V
Continuous Drain Current (Tc=25 $^\circ \!\! \mathbb{C}$ )	I <sub>D</sub>	20	-20	A
Continuous Drain Current (Tc=100 $^\circ \mathrm{C}$ )	I <sub>D</sub>	14.1	-14	А
Pulsed Drain Currenr <sup>(1)</sup>	I <sub>DM</sub>	80	-60	A
Power Dissipation	PD	2	21	w
Thermal Resistance from Junction to Ambient <sup>(2)</sup>	R <sub>θJA</sub>	6.25		°C/W
Junction Temperature	TJ	150		°C
Storage Temperature	T <sub>STG</sub>	-55~ +150		°C

#### Notes:

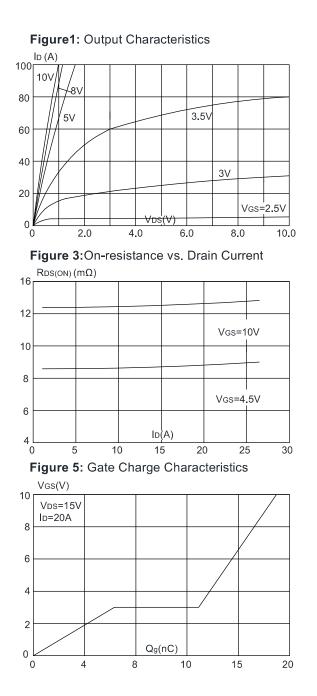
- 1) Repetitive Rating: pulse width limited by maximum junction temperature
- 2) The value of R<sub> $\theta$ JA</sub> Mounted on FR4 Board (25.4mm\*25.4mm\*t1.6mm) With 2oz Copper,Ta=25  $^{\circ}$ C

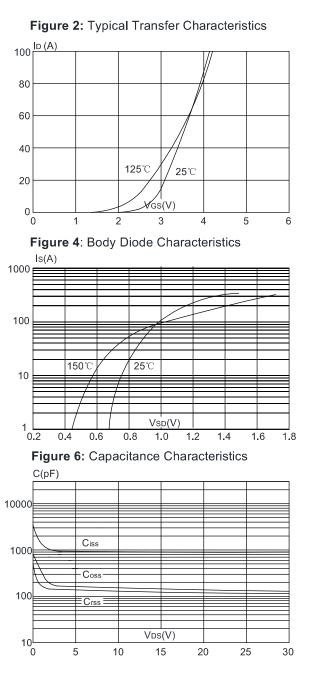


## N-CH ELECTRICAL CHARACTERISTICS(T<sub>J</sub>=25 $^{\circ}$ C unless otherwise noted)

Parameter	Symbol	Test Condition	Min	Туре	Max	Unit	
Static Characteristics							
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> =250µA	30			V	
Zero gate voltage drain current	I <sub>DSS</sub>	V <sub>DS</sub> =30V, V <sub>GS</sub> = 0V			1	μA	
Gate-body leakage current	IGSS	$V_{GS}$ = ±20V, $V_{DS}$ = 0V			±100	nA	
Gate threshold voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250µA	1	1.5	2.5	V	
		V <sub>GS</sub> =10V, I <sub>D</sub> =10A		10.5	14	— mΩ	
Drain-source on-resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =4.5V, I <sub>D</sub> =5A		17	22		
Forward tranconductance	<b>g</b> fs	V <sub>DS</sub> =10V, I <sub>D</sub> =10A		10		S	
Dynamic characteristics							
Input Capacitance	C <sub>iss</sub>			900			
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> =15V, V <sub>GS</sub> =0V, f =1MHz		140		pF	
Reverse Transfer Capacitance	C <sub>rss</sub>			120			
Switching characteristics			•				
Turn-on delay time	t <sub>d(on)</sub>			6			
Turn-on rise time	tr	V <sub>DD</sub> =15V, I <sub>D</sub> =10A		5		1	
Turn-off delay time	t <sub>d(off)</sub>	V <sub>GS</sub> =10V, R <sub>G</sub> =3Ω		25		- ns	
Turn-off fall time	t <sub>f</sub>	f		7			
Total Gate Charge	Qg			19			
Gate-Source Charge	Qgs	VDS=15V, ID=20A,		6.3		nC	
Gate-Drain Charge	Qgd	VGS=10V		4.5			
Source-Drain Diode characteristics	·		·	•			
Diode Forward voltage	V <sub>DS</sub>	V <sub>GS</sub> =0V, I <sub>S</sub> =10A			1.2	V	
Diode Forward current	Is		-	-	20	А	

### **Typical Performance Characteristics**







**Figure 7:** Normalized Breakdown Voltage vs. Junction Temperature

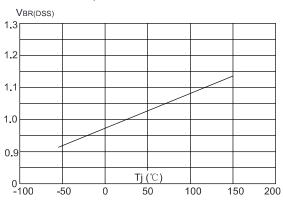
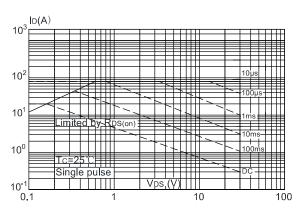
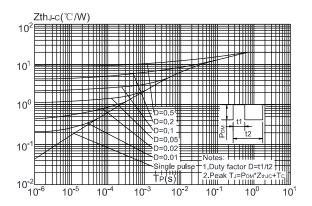


Figure 9: Maximum Safe Operating Area







**Figure 8:** Normalized on Resistance vs. Junction Temperature

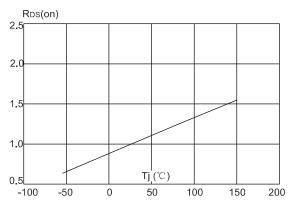
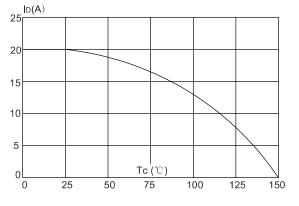
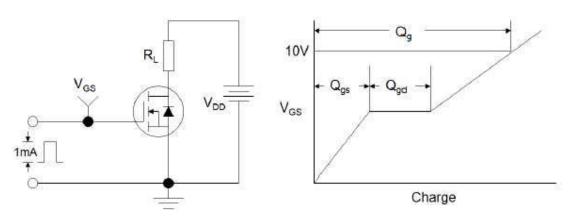


Figure 10: Maximum Continuous Drain Current vs. Case Temperature



## **Test Circuit**





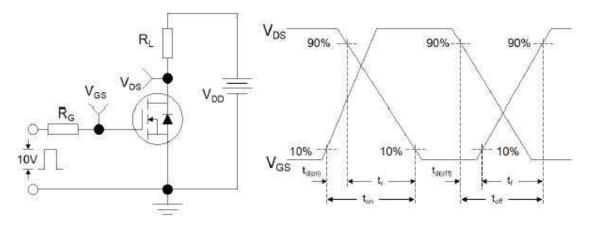


Figure 2: Resistive Switching Test Circuit & Waveforms

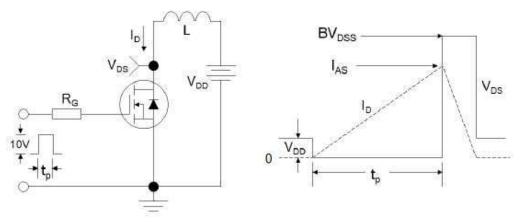
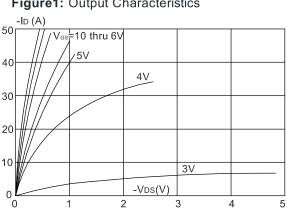


Figure 3: Unclamped Inductive Switching Test Circuit & Waveforms

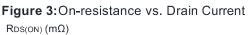
## P-CH ELECTRICAL CHARACTERISTICS(T\_J=25 $^\circ\!\!\!\mathrm{C}$ unless otherwise noted)

Parameter	Symbol	Test Condition	Min	Туре	Max	Unit	
Static Characteristics	·						
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> =-250µA	-30			V	
Zero gate voltage drain current	DSS	V <sub>DS</sub> =-30V, V <sub>GS</sub> = 0V			1	μA	
Gate-body leakage current	GSS	$V_{GS} = \pm 20V, V_{DS} = 0V$			±100	nA	
Gate threshold voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =-250µA	-1	-1.5	-2.5	V	
	Б	V <sub>GS</sub> =-10V, I <sub>D</sub> =-10A		17.5	23	mΩ	
Drain-source on-resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-5A		24	32		
Forward tranconductance	<b>g</b> fs	V <sub>DS</sub> =-10V, I <sub>D</sub> =-10A		20		S	
Dynamic characteristics							
Input Capacitance	C <sub>iss</sub>			1550			
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> =-15V, V <sub>GS</sub> =0V, f =1MHz		327		pF	
Reverse Transfer Capacitance	C <sub>rss</sub>	-		278			
Switching characteristics	·		•				
Turn-on delay time	t <sub>d(on)</sub>			14			
Turn-on rise time	tr	V <sub>DD</sub> =-15V, I <sub>D</sub> =-6A		20			
Turn-off delay time	t <sub>d(off)</sub>	V <sub>GS</sub> =-10V, R <sub>G</sub> =2.5Ω		95		- ns	
Turn-off fall time	t <sub>f</sub>	f		65			
Total Gate Charge	Qg			30			
Gate-Source Charge	Qgs	- VDS=-15V, ID=-10A, - VGS=-10V		5.3		nC	
Gate-Drain Charge	Qgd	- 100		7.6			
Source-Drain Diode characteristics							
Diode Forward voltage	V <sub>DS</sub>	V <sub>GS</sub> =0V, I <sub>S</sub> =-10A			1.2	V	
Diode Forward current	Is		-	-	-20	А	





#### Figure1: Output Characteristics



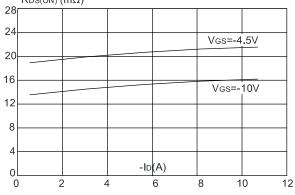
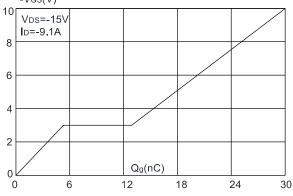


Figure 5: Gate Charge Characteristics -Vgs(V)



#### Figure 2: Typical Transfer Characteristics

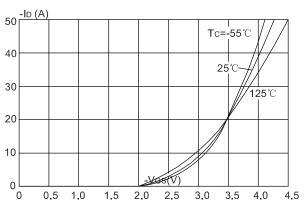


Figure 4: Body Diode Characteristics

-Is(A)

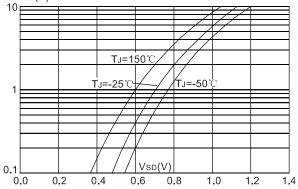
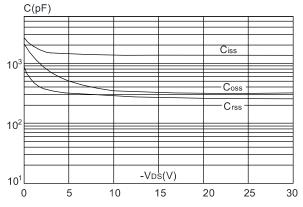


Figure 6: Capacitance Characteristics





**Figure 7:** Normalized Breakdown Voltage vs. Junction Temperature

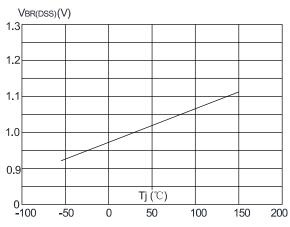
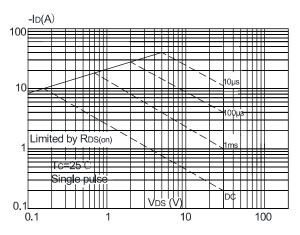
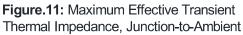
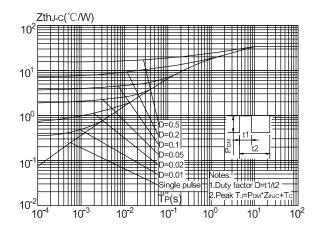


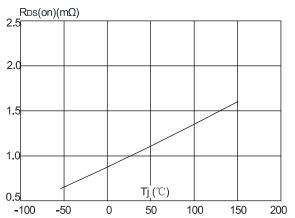
Figure 9: Maximum Safe Operating Area



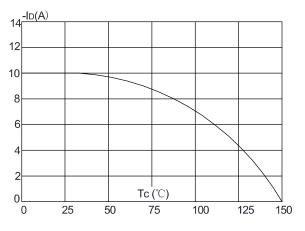




**Figure 8:** Normalized on Resistance vs. Junction Temperature

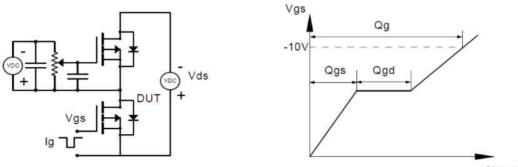






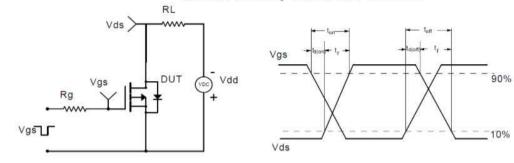


#### Gate Charge Test Circuit & Waveform

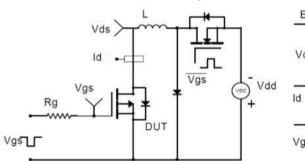


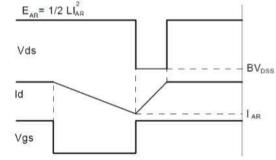
Charge

Resistive Switching Test Circuit & Waveforms

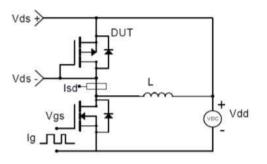


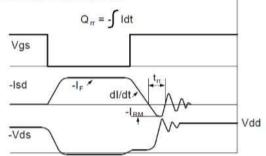
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms





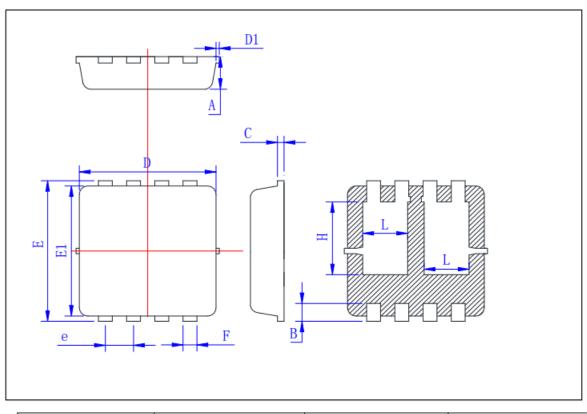








# PDFN3X3-D Package Information



Symbol	Min	Тур	Max
А	0.725	0.775	0.825
В	0.28	0.38	0.48
С	0.13	0.15	0.20
D	3.05	3.15	3.25
D1			0.10
Е	3.25	3.35	3.45
E1	3.0	3.1	3.2
e	0.60	0.65	0.70
F	0.27	0.32	0.37
Н	1.63	1.73	1.83
L	0.93	1.03	1.13



## **Revision History**

Revision	Release	Remark
V1.0	2024/05/10	Reset

## Disclaimer

The information given in this document describes the independent performance of the product,but similar performance is not guaranteed under other working conditions,and cannot be guaranteed when installed with other products or equipment. To achieve the required performance of the product in actual scenarios, the customer should conduct a complete application test to assess the functionality of the product.

Allpower assumes no responsibility for equipment failures result from using products at values that exceed the ratings, operating conditions, or other parameters listed in the product specifications.

The product described in this specification is not applicable for aerospace or other applications which

requires high reliability.Customers using or selling these products for use in medical,life-saving,or lifesustaining applications do so at their own risk and agree to fully indemnify.

Due to product or technical improvements, the information described or contained herein may be changed without prior notice.